



COMPLEMENTARY PAIR ENHANCEMENT MODE MOSFET

Product Summary

Device	V _{(BR)DSS}	R _{DS(ON)} max	I_D max $T_A = +25$ °C
Q1	30V	$27\text{m}\Omega$ @ $V_{GS} = 10V$	7.2A
		$35m\Omega$ @ $V_{GS} = 4.5V$	6.0A
Q2	-30V	$25m\Omega$ @ $V_{GS} = -10V$	-7.6A
		$41 \text{m}\Omega$ @ $V_{GS} = -4.5 \text{V}$	-6.2A

Features and Benefits

- Low Input Capacitance
- Low On-Resistance
- Fast Switching Speed
- Totally Lead-Free & Fully RoHS Compliant (Notes 1 & 2)
- Halogen and Antimony Free. "Green" Device (Note 3)
- Qualified to AEC-Q101 Standards for High Reliability

Description

This new generation MOSFET has been designed to minimize the onstate resistance ($R_{DS(ON)}$) and yet maintain superior switching performance, making it ideal for high efficiency power management applications.

Applications

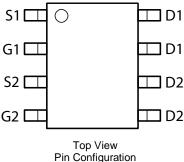
- DC-DC Converters
- Power Management Functions
- Backlighting

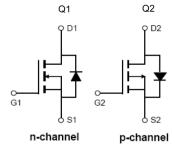
Mechanical Data

- Case: SO-8
- Case Material: Molded Plastic, "Green" Molding Compound.
 UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminal Connections: See Diagram
- Terminals: Finish Tin Finish annealed over Copper leadframe.
 Solderable per MIL-STD-202, Method 208 (3)
- Weight: 0.074 grams (approximate)









Equivalent Circuit

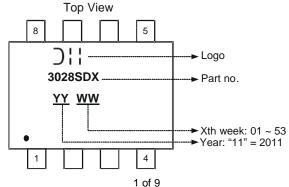
Ordering Information (Note 4)

Part Number	Case	Packaging		
DMC3028LSDX-13	SO-8	2,500/Tape & Reel		

Notes:

- 1. No purposely added lead. Fully EU Directive 2002/95/EC (RoHS) & 2011/65/EU (RoHS 2) compliant.
- See http://www.diodes.com/quality/lead_free.html for more information about Diodes Incorporated's definitions of Halogen- and Antimony-free, "Green" and Lead-free.
- 3. Halogen- and Antimony-free "Green" products are defined as those which contain <900ppm bromine, <900ppm chlorine (<1500ppm total Br + Cl) and <1000ppm antimony compounds.
- ${\it 4. For packaging details, go to our website at http://www.diodes.com/products/packages.html.}\\$

Marking Information





Maximum Ratings - Q1 and Q2 (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Q1	Q2	Units		
Drain-Source Voltage	V_{DSS}	30	-30	V		
Gate-Source Voltage	V_{GSS}	±20	±20	V		
Continuous Prais Current (Note 5) // 40//	Steady State	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	5.5 4.1	-5.8 -4.3	А
Continuous Drain Current (Note 5) V _{GS} =10V	t<10s	$T_A = +25^{\circ}C$ $T_A = +70^{\circ}C$	I _D	7.2 5.7	-7.6 -6.1	А
Maximum Body Diode Forward Current (Note 5)	Is	2.2	-2.2	Α		
Pulsed Drain Current (10µs pulse, duty cycle = 1%)			I _{DM}	40	-30	Α

Thermal Characteristics ($@T_A = +25^{\circ}C$, unless otherwise specified.)

Characteristic	Symbol	Value	Units	
Total Dawar Dissipation (Note 5)	T _A = +25°C	Б	1.2	W
Total Power Dissipation (Note 5)	T _A = +70°C	P_{D}	0.75	
Thermal Resistance, Junction to Ambient (Note 5)	Steady state	D	108	°C/W
Thermal Resistance, Junction to Ambient (Note 5)	t<10s	R• JA	65	
Total Power Dissipation (Note 6)	$T_A = +25^{\circ}C$	Ъ	1.5	W
Total Fower Dissipation (Note o)	T _A = +70°C	P_{D}	0.95	
Thermal Resistance, Junction to Ambient (Note 6)	Steady state	D-	85	°C/W
Thermal Resistance, Junction to Ambient (Note 6)	t<10s	Reja	50	
Thermal Resistance, Junction to Case (Note 6)		Rejc	14.5	
Operating and Storage Temperature Range		$T_{J_1}T_{STG}$	-55 to +150	°C

Electrical Characteristics — Q1 (@T_A = +25°C, unless otherwise specified.)

Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition
OFF CHARACTERISTICS (Note 8)						
Drain-Source Breakdown Voltage	BV _{DSS}	30	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
Zero Gate Voltage Drain Current	I _{DSS}	1	_	1	μA	$V_{DS} = 24V, V_{GS} = 0V$
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$
ON CHARACTERISTICS (Note 8)						
Gate Threshold Voltage	V _{GS(th)}	1	_	3	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Static Drain-Source On-Resistance	D		19	27	mΩ	$V_{GS} = 10V, I_D = 6A$
Static Drain-Source On-Resistance	R _{DS (ON)}	1	22	35	1115.2	$V_{GS} = 4.5V, I_D = 5A$
Diode Forward Voltage	V_{SD}	_	0.7	1.2	V	$V_{GS} = 0V, I_{S} = 1.3A$
DYNAMIC CHARACTERISTICS (Note 9)						
Input Capacitance	Ciss		641	_		V _{DS} = 15V, V _{GS} = 0V f = 1.0MHz
Output Capacitance	Coss		66		рF	
Reverse Transfer Capacitance	C _{rss}		51	_		
Gate Resistance	R_{G}	_	2.2	_	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$
Total Gate Charge (V _{GS} = 4.5V)	Q_g	_	6	_		V _{DS} = 15V, I _D = 10A
Total Gate Charge (V _{GS} = 10V)	Qg	_	13.2	_	nC	
Gate-Source Charge	Q_{gs}	_	1.7	_	IIC	
Gate-Drain Charge	Q _{gd}		2.2	_		
Turn-On Delay Time	t _{D(on)}	_	3.3	_		
Turn-On Rise Time	t _r		4.4	_	nS	$V_{GS} = 10V, V_{DD} = 15V, R_G = 6\Omega,$
Turn-Off Delay Time	t _{D(off)}		22.3	_	115	I _D = 1A
Turn-Off Fall Time	t _f	_	5.3	_		

Notes:

- 5. Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.
- Device mounted on FR-4 substrate PC board, 202 copper, with minimum recommended particles.
 Leg mounted on FR-4 substrate PC board, 202 copper, with 1inch square copper plate.
 I_{AR} and E_{AR} rating are based on low frequency and duty cycles to keep T_J = +25°C
 Short duration pulse test used to minimize self-heating effect.
 Guaranteed by design. Not subject to product testing.



Electrical Characteristics — Q2 (@T_A = +25°C, unless otherwise specified.)

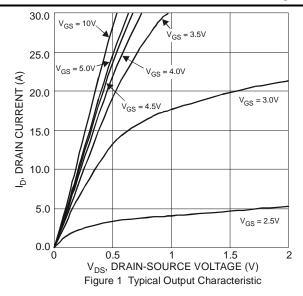
Characteristic	Symbol	Min	Тур	Max	Unit	Test Condition	
OFF CHARACTERISTICS (Note 8)							
Drain-Source Breakdown Voltage	BV _{DSS}	-30		_	V	$V_{GS} = 0V, I_D = -250\mu A$	
Zero Gate Voltage Drain Current	I _{DSS}		_	-1	μA	$V_{DS} = -24V, V_{GS} = 0V$	
Gate-Source Leakage	I _{GSS}	_	_	±100	nA	$V_{GS} = \pm 20V, V_{DS} = 0V$	
ON CHARACTERISTICS (Note 8)							
Gate Threshold Voltage	V _{GS(th)}	-1	_	-3	V	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	
Static Drain-Source On-Resistance	J.		21	25	~ 0	$V_{GS} = -10V, I_D = -6A$	
Static Drain-Source On-Resistance	R _{DS (ON)}	_	29	41	mΩ	$V_{GS} = -4.5V, I_D = -5A$	
Diode Forward Voltage	V_{SD}	_	-0.7	-1.2	V	$V_{GS} = 0V, I_{S} = -1.3A$	
DYNAMIC CHARACTERISTICS (Note 9)							
Input Capacitance	C _{iss}		1241	_		$V_{DS} = -15V, V_{GS} = 0V$ f = 1.0MHz	
Output Capacitance	Coss	_	146	_	pF		
Reverse Transfer Capacitance	C _{rss}	_	110	_			
Gate Resistance	R_{G}	_	14.8	_	Ω	$V_{DS} = 0V, V_{GS} = 0V, f = 1.0MHz$	
Total Gate Charge (V _{GS} = -4.5V)	Qg	_	10.9	_			
Total Gate Charge (V _{GS} = -10V)	Qg	_	22	_	nC	$V_{DS} = -15V, I_{D} = -7A$	
Gate-Source Charge	Q _{gs}	_	3.5	_	IIC		
Gate-Drain Charge	Q_{gd}	_	4.7	_			
Turn-On Delay Time	t _{D(on)}	_	9.7	_			
Turn-On Rise Time	t _r	_	17.1	_	nS	$V_{GS} = -10V, V_{DD} = -15V, R_{GEN} = 6\Omega,$	
Turn-Off Delay Time	t _{D(off)}	_	60.5	_	115	I _D = -7A	
Turn-Off Fall Time	t _f		40.4	_			

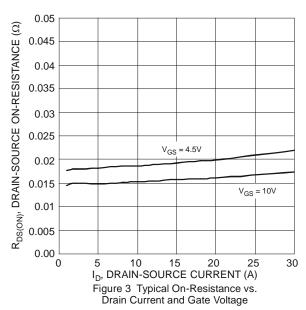
Notes:

^{8.} Short duration pulse test used to minimize self-heating effect. 9. Guaranteed by design. Not subject to product testing.



N-Channel - Q1





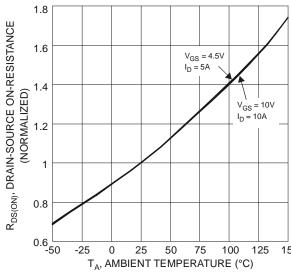
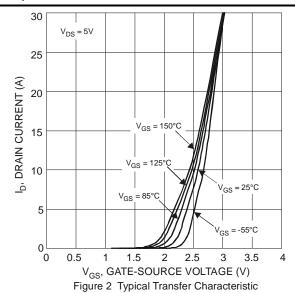


Figure 5 On-Resistance Variation with Temperature



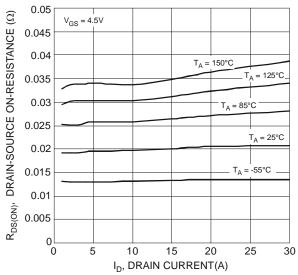


Figure 4 Typical On-Resistance vs. Drain Current and Temperature

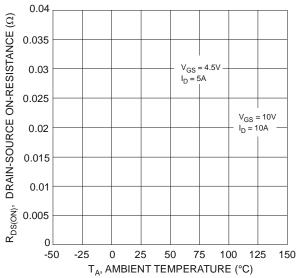


Figure 6 On-Resistance Variation with Temperature



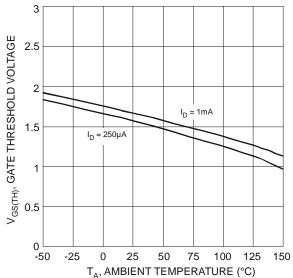


Figure 7 Gate Threshold Variation vs. Ambient Temperature

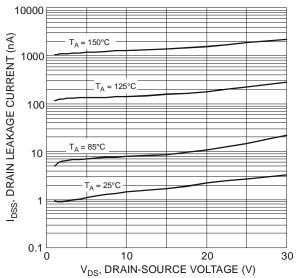


Figure 9 Typical Drain-Source Leakage Current vs. Voltage

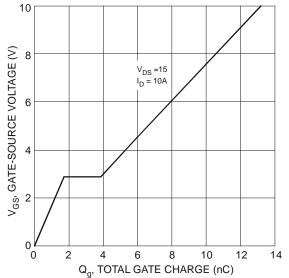
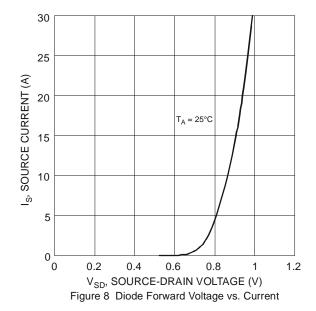
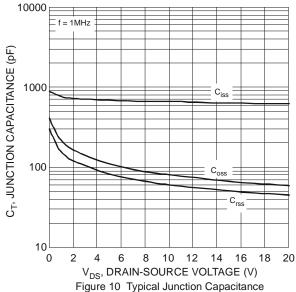


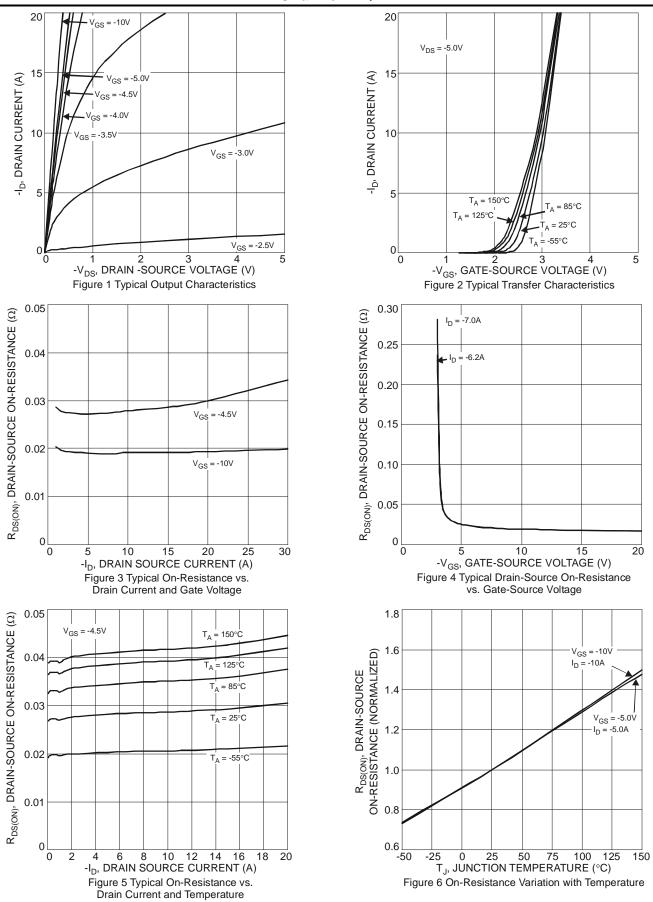
Figure 11 Gate-Source Voltage vs. Total Gate Charge







P-Channel - Q2





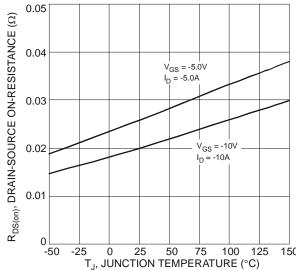
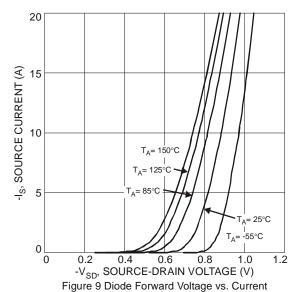


Figure 7 On-Resistance Variation with Temperature



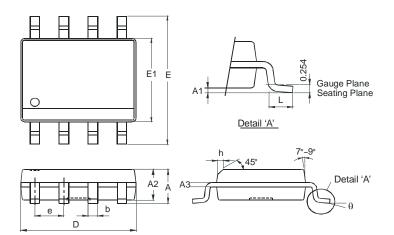
3.0 (S) 2.5 ON 2.0 ON 2.0 ON 2.0 ON 2.0 ON 1.5

Figure 8 Gate Threshold Variation vs. Ambient Temperature



Package Outline Dimensions

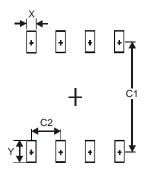
Please see AP02002 at http://www.diodes.com/datasheets/ap02002.pdf for latest version.



SO-8						
Dim	Min	Max				
Α	-	1.75				
A1	0.10	0.20				
A2	1.30	1.50				
A3	0.15 0.25					
b	0.3	0.5				
D	4.85	4.95				
Е	5.90	6.10				
E1	3.85	3.95				
е	1.27 Typ					
h	-	0.35				
L	0.62	0.82				
Θ	0°	8°				
All Dimensions in mm						

Suggested Pad Layout

Please see AP02001 at http://www.diodes.com/datasheets/ap02001.pdf for the latest version.



Dimensions	Value (in mm)				
Х	0.60				
Y	1.55				
C1	5.4				
C2	1.27				



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